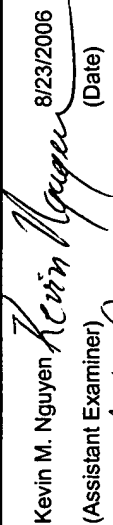
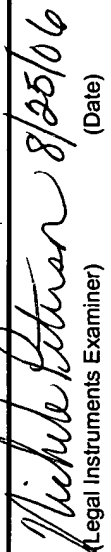

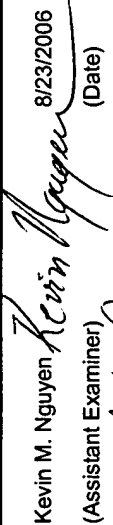
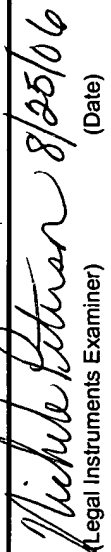

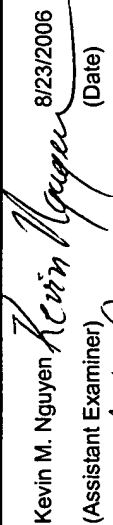
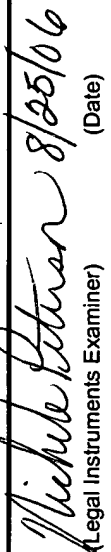

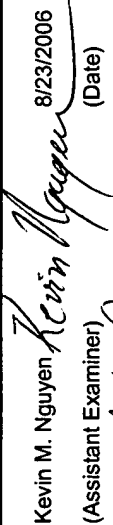
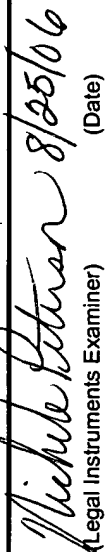

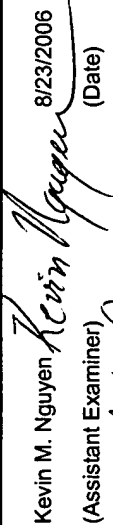
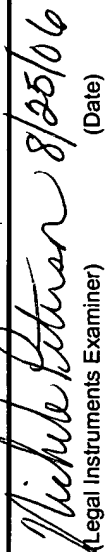

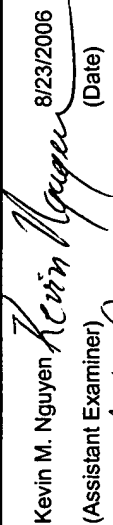
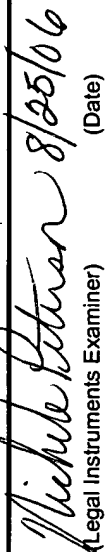

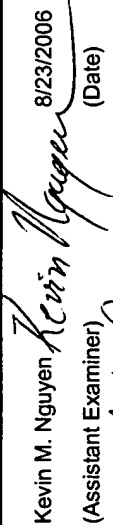
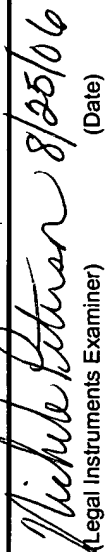

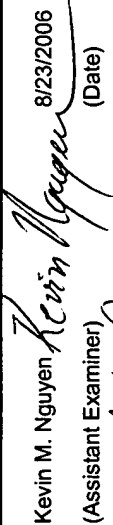
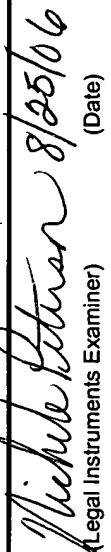

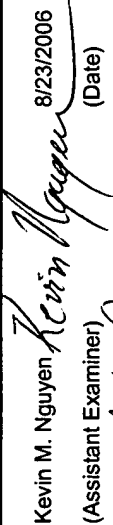
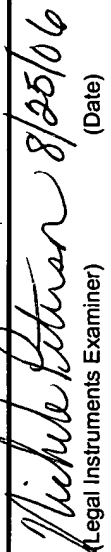

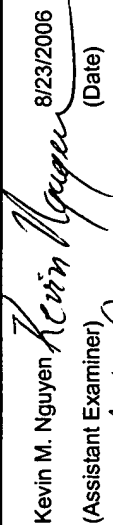
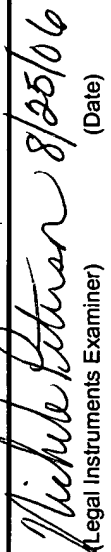

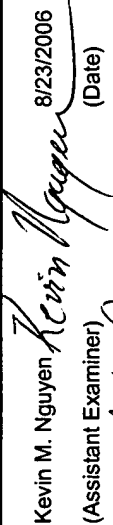
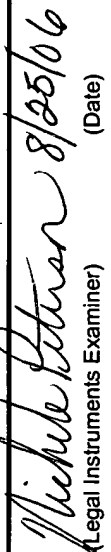

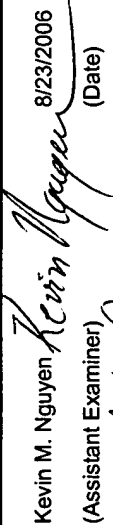
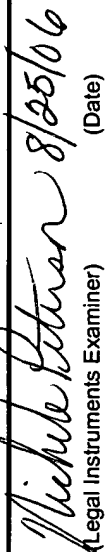

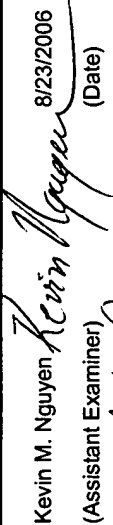
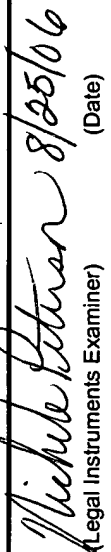



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Applicant(s)/Patent under Reexamination
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